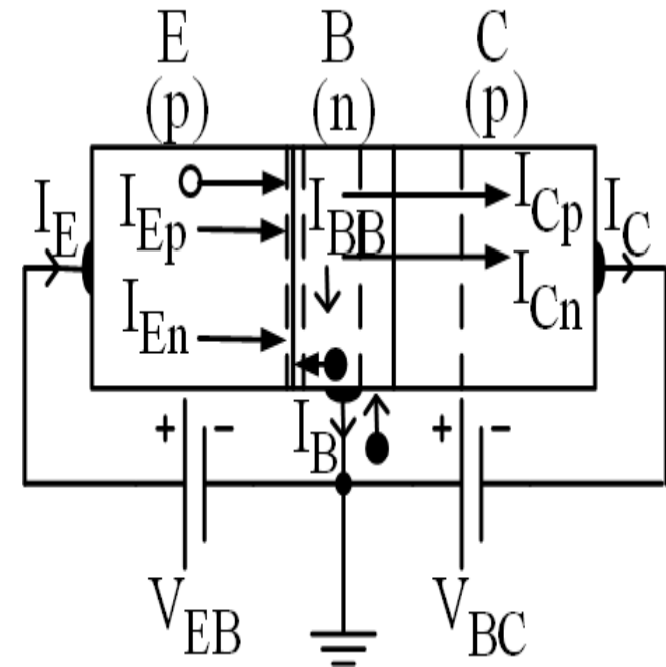


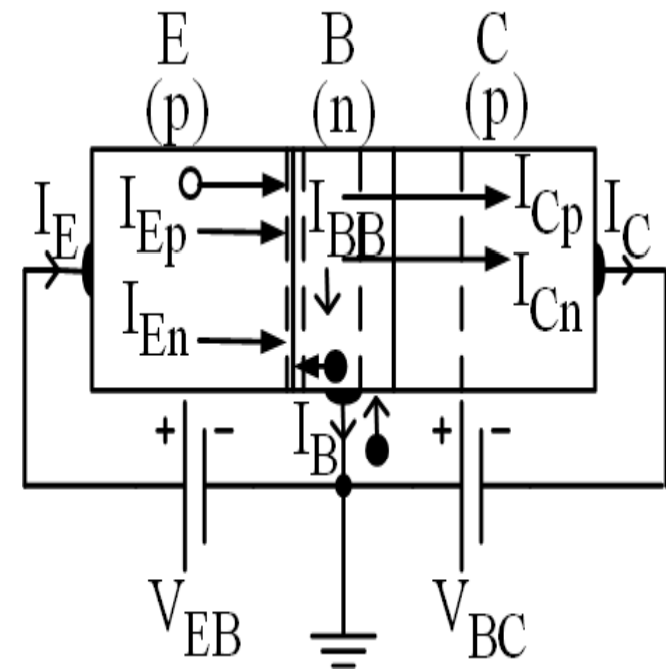
CLASS 17

BJT currents and parameters

- $I_E = I_{Ep} + I_{En}$
- $I_C = I_{Cp} + I_{Cn}$
- $I_B = I_{BB} + I_{En} - I_{Cn}$
- $I_{BB} = I_{Ep} - I_{Cp}$
- $I_E = I_B + I_C$
- I_{En} = current produced by the electrons injected from B to E
- I_{Cn} = current from the electrons thermally generated near the edge of the C-B junction that drifted from C to B.
- $I_B = I_E - I_C$
- $= I_{Ep} + I_{En} - I_{Cp} - I_{Cn}$
- $= I_{Ep} - I_{Cp} + I_{En} - I_{Cn}$
- $= I_{BB} + I_{En} - I_{Cn}$



- An important BJT parameter is the common-base (CB) current gain, α_o .
- $\alpha_o = I_{Cp} / I_E$
 $= I_{Cp} / (I_{Ep} + I_{En})$
 $= I_{Cp} I_{Ep} / [I_{Ep}(I_{Ep} + I_{En})]$
 $= [I_{Ep} / (I_{Ep} + I_{En})][I_{Cp} / I_{Ep}]$
 $= \gamma \alpha_T$
- Emitter efficiency, $\gamma = I_{Ep} / (I_{Ep} + I_{En})$
 $= I_{Ep} / I_E$
- Base transport factor, $\alpha_T = I_{Cp} / I_{Ep}$
- Since $\alpha_o = \gamma \alpha_T$ and $I_{En} \ll I_{Ep}$, then $I_{Ep} \approx I_E$. Hence, $\gamma \approx 1$.
- $I_{Cp} \approx I_{Ep}$. Thus, $\alpha_T \approx 1$. Consequently, $\alpha_o \approx 1$.



- $I_C = I_{Cp} + I_{Cn}$
- As $\alpha_T = I_{Cp} / I_{Ep}$, $I_C = \alpha_T I_{Ep} + I_{Cn}$
- Since $\alpha_o = \gamma \alpha_T$ and $\gamma = I_{Ep} / I_E$:

$$I_C = (\alpha_o / \gamma) \gamma I_E + I_{Cn}$$

$$I_C = \alpha_o I_E + I_{Cn}$$

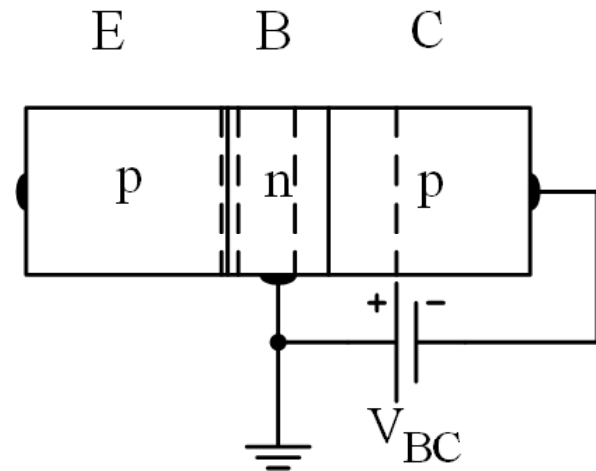
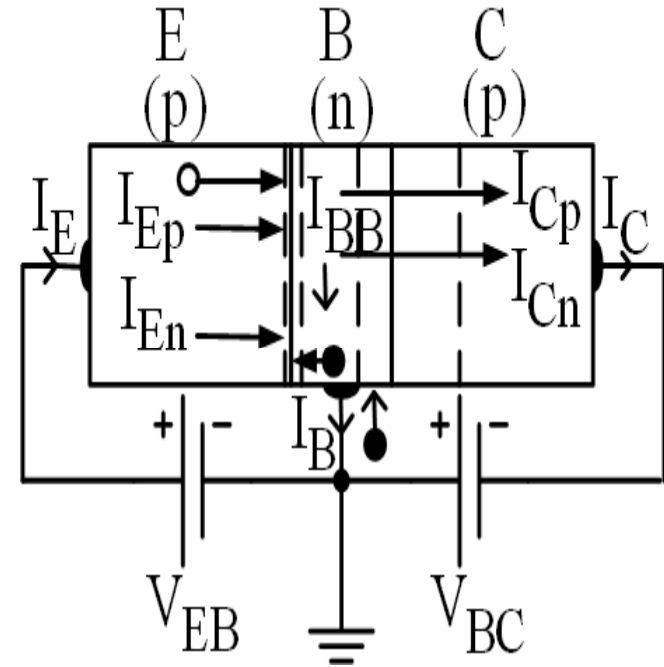
$$I_E = I_B + I_C$$

I_{Cn} can be determined by measuring the current flowing across the B-C junction when E is an open-circuit. $I_E = 0$.

The value of I_{Cn} under this condition is known as I_{CBO} . I_{CBO} represents the leakage current between C and B when E-B is open circuited.

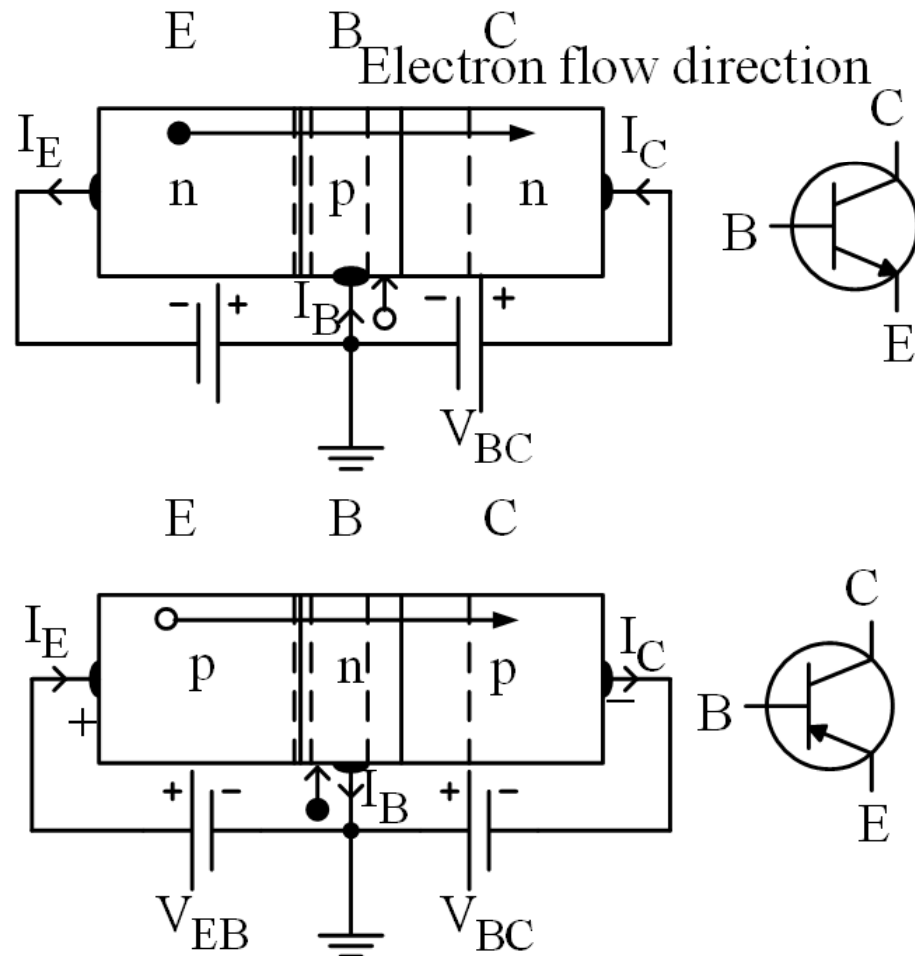
- Collector current for the CB configuration is represented by the expression:

$$I_C = \alpha_o I_E + I_{CBO}$$



- The conventional current flow is always in the opposite direction as the flow of electron.
- The conventional current flow is always in the same direction as the flow of holes.
- The flow of holes is always opposite with the flow of electrons.
- The general equation that relates the emitter, collector and base currents is:

$$I_E = I_B + I_C$$



Holes are injected from E to B when the E-B junction is fb. Holes will then diffuse across B and reach the B-C junction.

$$P_n(0) = p_{no} e^{(qV_{EB})/kT}$$

where:

p_{no} = density of the minority carriers under equilibrium condition.

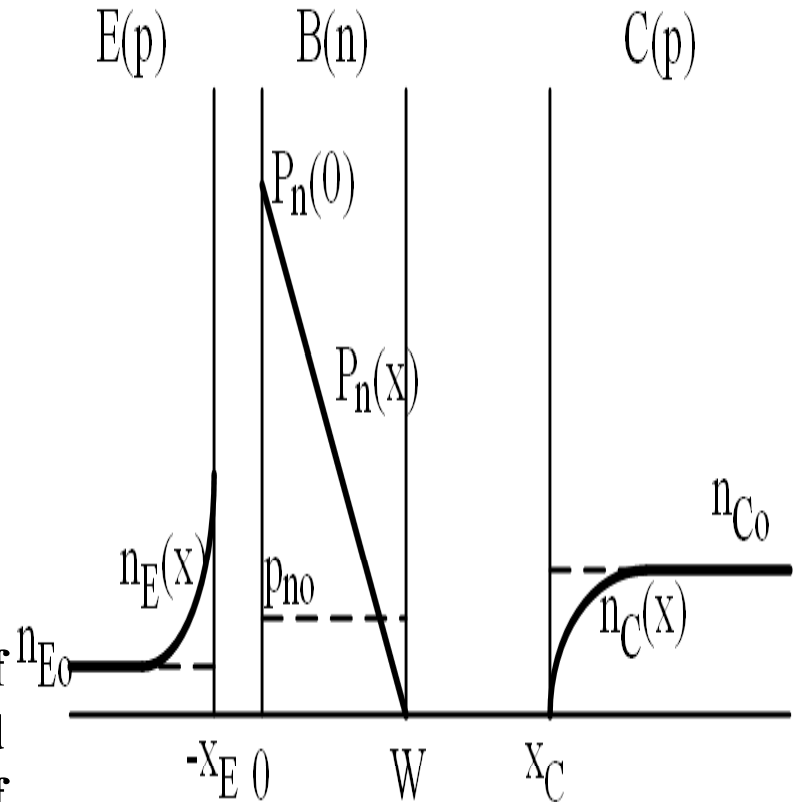
$$= n_i^2/N_B$$

N_B = donor density in B.

kT/q = temperature equivalent voltage

The existence of the density gradient of holes in B shows that the holes injected from E will diffuse across B to the edge of the B-C depletion region before they are swept into C by the electric field across B-C.

Distribution of the minority carriers in an active mode pnp transistor



$$P_n(0) = p_{no} e^{(qV_{EB})/kT}$$

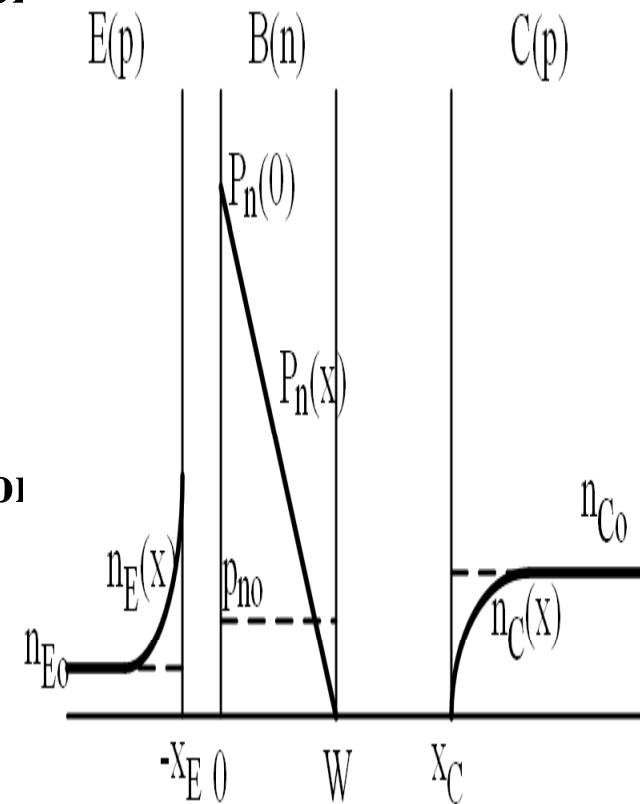
- If the E-B junction is fb, the minority carrier density at the edge of the E-B depletion region (at $x=0$) is increased beyond its equilibrium value by a factor of :

$$e^{(qV_{EB})/kT}$$

- $P_n(W) = 0$
- Under the rb condition, the minority carrier density at the edge of the B-C depletion region ($x = W$) is 0.
- If the B is very narrow (i.e. $W/L_p \ll 1$):

$$P_n(x) = p_{no} e^{(qV_{EB})/kT} [1 - (x/W)]$$

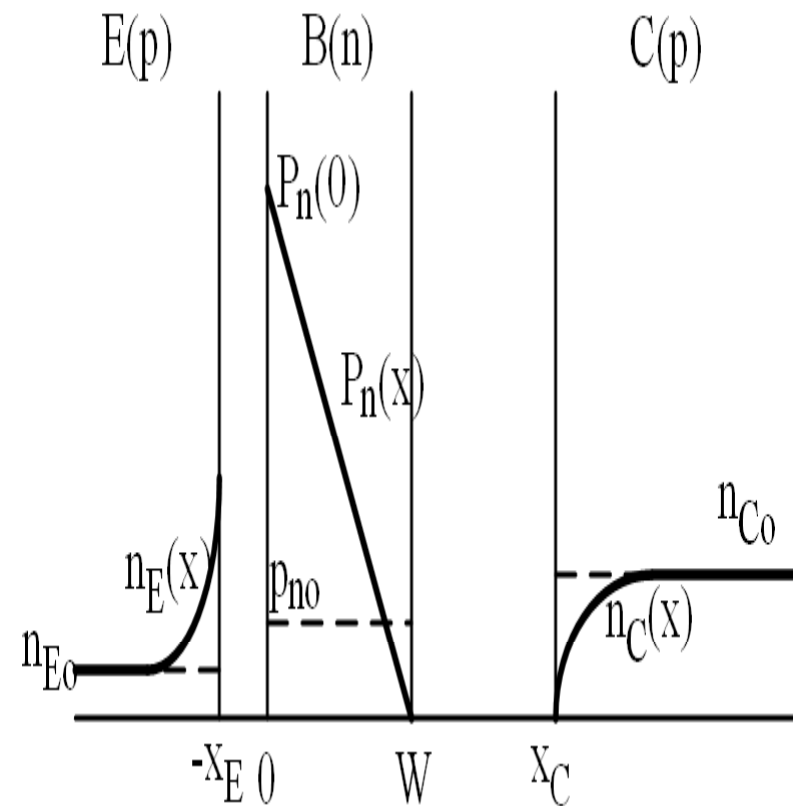
Distribution of the minority carriers in an active mode pnp transistor



$$P_n(x) = p_{no} e^{(qV_{EB})/kT} [1 - (x/W)]$$

This expression is close to the real minority carrier distribution in B. The assumption that the minority carrier distribution in B is linear simplifies the derivation of the I-V characteristic.

Distribution of the minority carriers in an active mode pnp transistor



$$n_E(x = -x_E) = n_{E0} e^{(qV_{EB})/kT}$$

$$n_C(x = x_C) = n_{C0} e^{|-qV_{CB}|/kT} = 0$$

where n_{E0} and n_{C0} are the electron densities under equilibrium condition for the E and C, respectively.

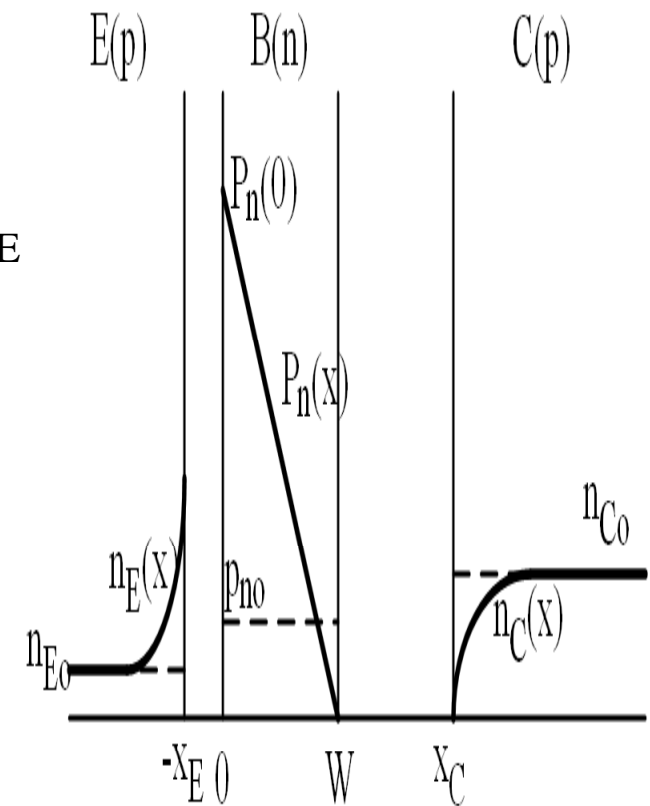
$$n_E(x) = n_{E0} + n_{E0} \left[e^{(qV_{EB})/kT} - 1 \right] e^{(x + x_E)/L_E}$$

for $x \leq -x_E$

$$n_C(x) = n_{C0} - n_{C0} e^{-(x - x_C)/L_C}$$

for $x \geq x_C$

Distribution of the minority carriers in an active mode pnp transistor



Transistor currents in the active mode of operation

The hole current, I_{Ep} , injected from E at $x=0$ is proportional to the gradient of the minority carrier density.

$$I_{Ep} = A \left[-qD_p \frac{dp_n}{dx} \Big|_{x=0} \right]$$

$$\approx \frac{qAD_p p_{no}}{W} e^{(qV_{EB})/kT}$$

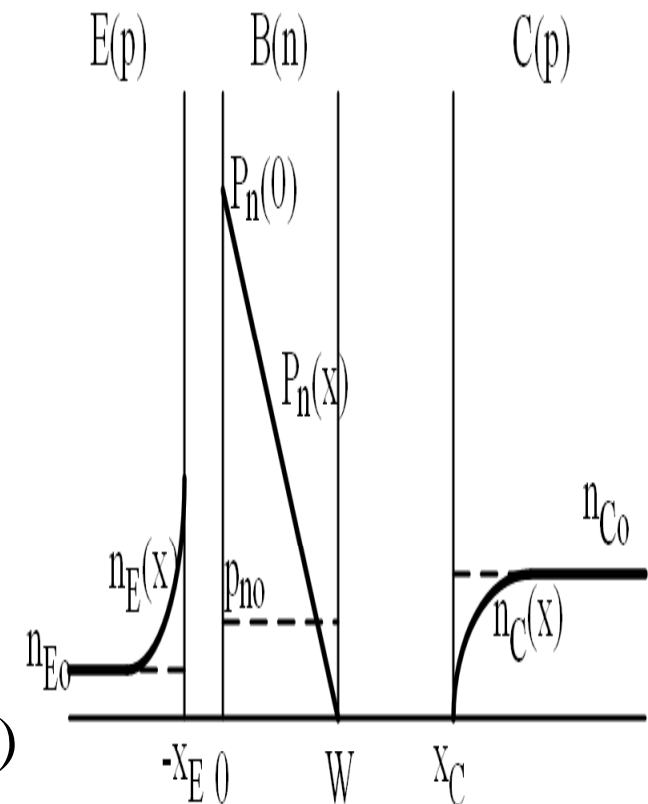
The hole current collected by C at $x=W$ is

$$I_{Cp} = A \left[-qD_p \frac{dp_n}{dx} \Big|_{x=W} \right]$$

$$\approx \frac{qAD_p p_{no}}{W} e^{(qV_{EB})/kT}$$

$$I_{Ep} = I_{Cp} \text{ for } \frac{W}{L_p} \ll 1 \text{ (i.e. when B is narrow)}$$

Distribution of the minority carriers in an active mode pnp transistor



I_{En} is produced by the flow of electrons from B to E.

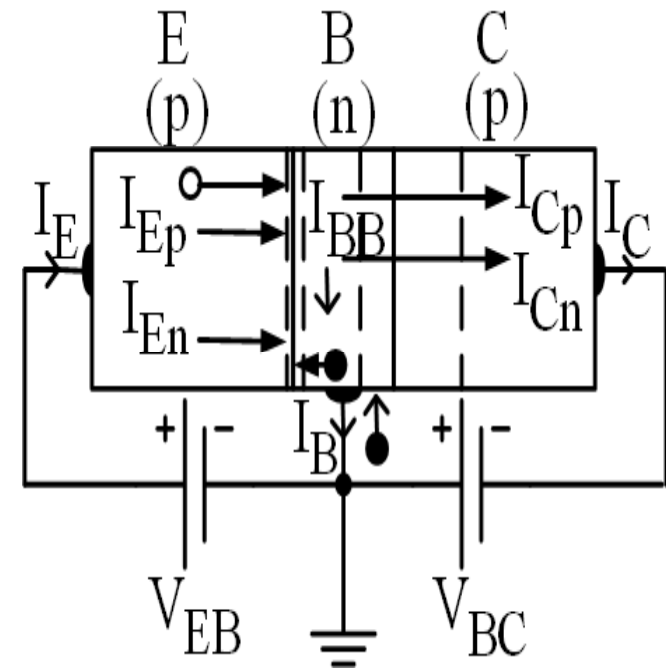
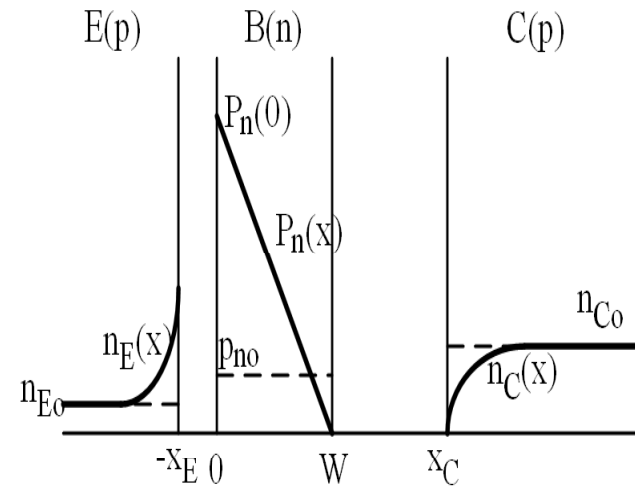
$$I_{En} = A \left[qD_E \frac{dn_E}{dx} \Big|_{x=-x_E} \right]$$

$$= \frac{qAD_E n_{E0}}{L_E} \left[e^{(qV_{EB})/kT} - 1 \right]$$

L_E is the diffusion length of the electron in the E.

D_E is the diffusion constant for the electron in E.

Distribution of the minority carriers in an active mode pnp transistor



I_{Cn} is produced by the flow of electrons from C to B.

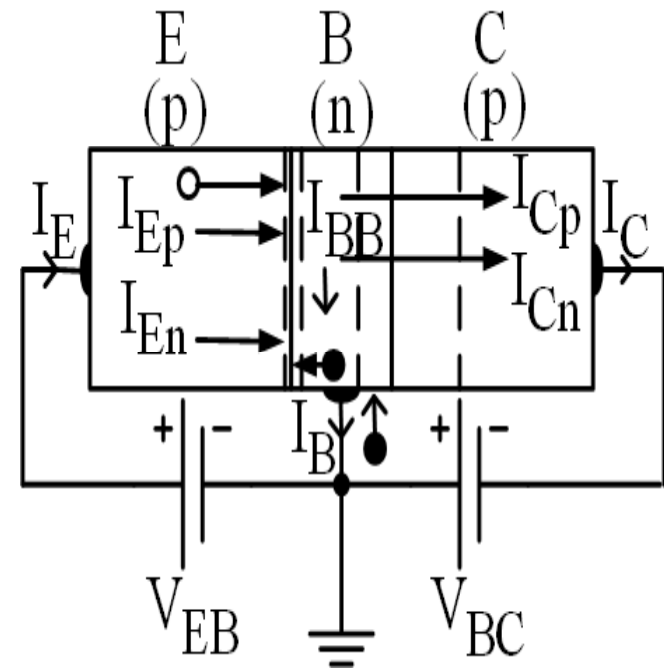
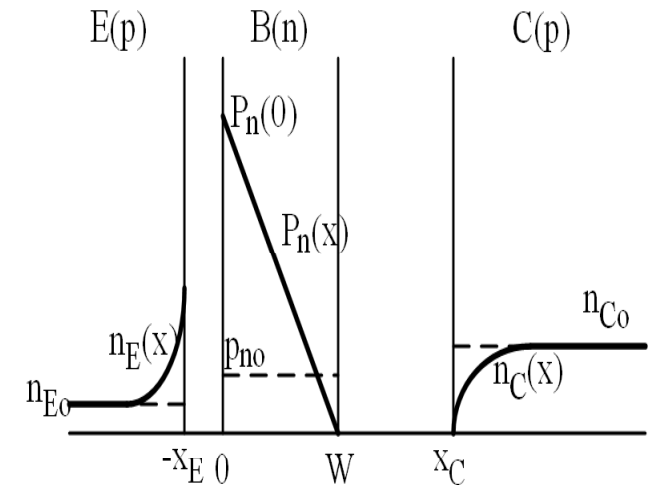
$$I_{Cn} = A \left[qD_C \frac{dn_C}{dx} \Big|_{x=x_C} \right]$$

$$= \frac{qAD_C n_{C0}}{L_C}$$

L_C is the diffusion length of the electron in the C.

D_C is the diffusion constant for the electron in C.

Distribution of the minority carriers in an active mode pnp transistor



$$\begin{aligned}
 I_E &= I_{Ep} + I_{En} \\
 &= \frac{qAD_p p_{no}}{W} e^{(qV_{EB})/kT} + \frac{qAD_E n_{Eo}}{L_E} \left[e^{(qV_{EB})/kT} - 1 \right]
 \end{aligned}$$

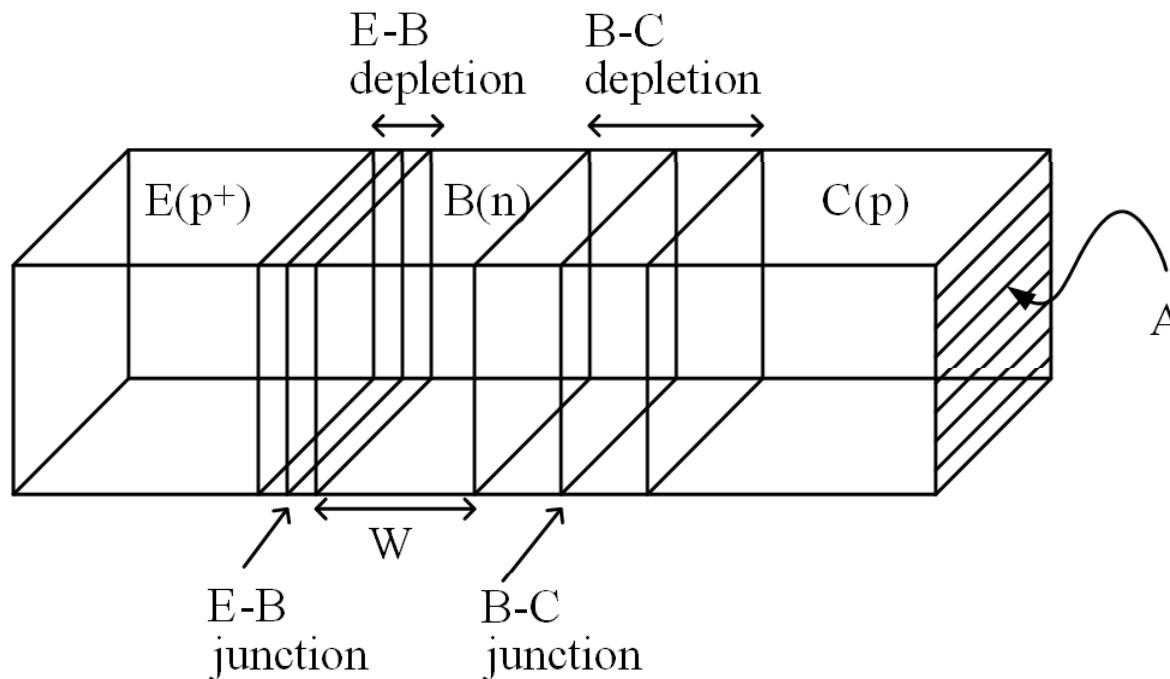
$$\begin{aligned}
 I_C &= I_{Cp} + I_{Cn} \\
 &= \frac{qAD_p p_{no}}{W} e^{(qV_{EB})/kT} + \frac{qAD_C n_{Co}}{L_C}
 \end{aligned}$$

$$\begin{aligned}
 I_B &= I_E - I_C \\
 &= \frac{qAD_E n_{Eo}}{L_E} \left[e^{(qV_{EB})/kT} - 1 \right] - \frac{qAD_C n_{Co}}{L_C}
 \end{aligned}$$

- The current in each terminal (E,B and C) is determined mostly by the minority carrier distribution in B.
- I_C is independent of V_{BC} as long as the B-C junction is rb.
- If it is assumed that there is no recombination in B, $I_{EP} = I_{CP}$. Hence,
- $I_{BB} = I_{Ep} - I_{Cp} = 0$
- $I_B = I_{BB} + I_{En} - I_{Cn} = I_{En} - I_{Cn}$

QUESTION

The p^+n-p transistor has 10^{19} , 10^{17} and $5 \times 10^{15} \text{ cm}^{-3}$ impurity density in each E, B and C, respectively. The lifetime is 10^{-8} , 10^{-7} and 10^{-6} s. Assume that the cross-section area, $A = 0.05 \text{ mm}^2$ and the E-B junction is fb by a 0.6 V. Determine the common-base (CB) current gain, α_o . Other device parameters are $D_E = 1 \text{ cm}^2/\text{s}$, $D_B = 10 \text{ cm}^2/\text{s}$, $D_C = 2 \text{ cm}^2/\text{s}$, intrinsic electron-hole pair density = 9.65×10^9 and $W = 0.5 \text{ }\mu\text{m}$.

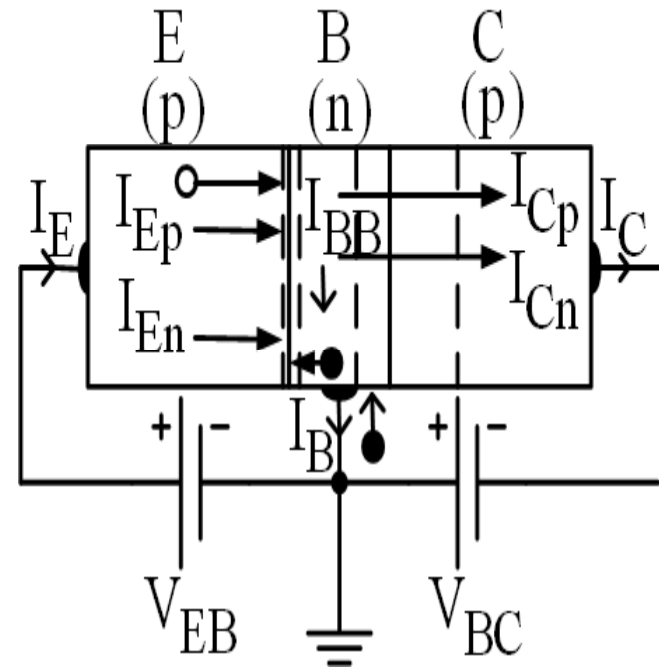


$$\alpha_o = \frac{I_{Cp}}{I_E}$$

$$I_E = I_{Ep} + I_{En}$$

$$= qA \left\{ \frac{D_p p_{no}}{W} e^{(qV_{EB})/kT} + \frac{D_E n_{Eo}}{L_E} \left[e^{(qV_{EB})/kT} - 1 \right] \right\}$$

$$I_{Cp} = \frac{qAD_p p_{no}}{W} e^{(qV_{EB})/kT}$$



D_p = diffusion constant of hole in B = 10 cm²/s

p_{no} = hole minority carriers in B during thermal equilibrium

$$p_{no} = n_i^2/N_B = (9.65 \times 10^9)^2/10^{17} = 931.225 \text{ cm}^{-3}$$

D_E = electron diffusion coefficient in E = 1 cm²/s

n_{Eo} = electron minority carrier in E during thermal equilibrium

$$n_{Eo} = n_i^2/N_E = (9.65 \times 10^9)^2/10^{19} = 9.3122 \text{ cm}^{-3}$$

L_E = electron diffusion length in E

$$L_E = \sqrt{D_E \tau_E} = \sqrt{1 \text{ cm}^2/\text{s} \left(10^{-8} \text{ s} \right)} = 10^{-4} \text{ cm}$$

$$I_{Cp} = I_{Ep} = \frac{\left(1.6 \times 10^{-19} \text{ C} \right) \left(0.05 \times 10^{-2} \text{ cm}^2 \right) \left(10 \text{ cm}^2/\text{s} \right) \left(931.225 \text{ cm}^{-3} \right) e^{(qV_{EB})/kT}}{\left(0.5 \times 10^{-4} \text{ cm} \right)}$$

$$I_{Cp} = I_{Ep} = 1.49 \times 10^{-14} \times 1.1505 \times 10^{10} \text{ A}$$
$$= 1.7142 \times 10^{-4} \text{ A}$$

$$I_{En} = \frac{\left(1.6 \times 10^{-19} \text{ C}\right) \left(0.05 \times 10^{-2} \text{ cm}^2\right) \left(1 \text{ cm}^2 / \text{s}\right) \left(9.3122 \text{ cm}^{-3}\right)}{\left(10^{-4} \text{ cm}\right)} \left(1.1505 \times 10^{10} - 1\right)$$

$$= 8.5709 \times 10^{-8} \text{ A}$$

$$\alpha_o = \frac{I_{Cp}}{I_E} = \frac{1.7142 \times 10^{-4}}{1.715 \times 10^{-4}} = 0.9995$$

Emitter efficiency, $\gamma = I_{Ep} / (I_{Ep} + I_{En})$
 $= I_{Ep} / I_E$

In the case of narrow Base, $I_{Ep} = I_{Cp}$

Thus, $\gamma = \alpha_o$.

